



PFE1A21NS

## PFE1A21NS

### 100V N-Channel MOSFET

#### FEATURES

- 100V / 52A  
 $R_{DS(ON)} = 17.5mR(\text{Max.}) @ V_{GS} = 10V$   
 $R_{DS(ON)} = 21.0mR(\text{Max.}) @ V_{GS} = 4.5V$
- 100% UIS & R<sub>G</sub> Tested
- Lead Free and Green Devices Available

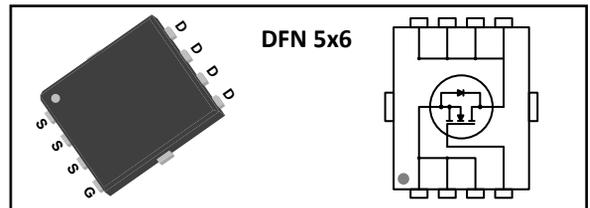
**BV<sub>DSS</sub> = 100 V**

**R<sub>DS(ON)</sub> = 14.5 mR**

**I<sub>D</sub> = 52 A**

#### APPLICATION

- DC-DC Converter
- Motor Control



#### Absolute Maximum Ratings T<sub>J</sub>=25 °C unless otherwise specified

Symbol	Parameter	Rating	Units
V <sub>DSS</sub>	Drain-Source Voltage	100	V
I <sub>D</sub>	Drain Current – Continuous (T <sub>c</sub> = 25 °C)*	52	A
	Drain Current – Continuous (T <sub>c</sub> = 100 °C)*	33	
I <sub>DM</sub>	Drain Current – Pulsed	130	A
V <sub>GS</sub>	Gate-Source Voltage	±20	V
P <sub>D</sub>	Maximum Power Dissipation (T <sub>c</sub> = 25 °C)*	96	W
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range	-55 to +150	°C

#### Thermal Characteristics

Symbol	Parameter	Rating	Unit
R <sub>THJC</sub>	Thermal Resistance, Junction to Ambient*	1.3	°C/W

#### Package Marking and Ordering Information

Marking	Device	Package	Remark
1A21NS	PKE1A21NS	DFN 5x6	halogen Free

**Electrical Characteristics**  $T_c=25\text{ }^\circ\text{C}$  unless otherwise specified

Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
--------	-----------	-----------------	-----	-----	-----	-------

**On Characteristics**

$V_{GS(TH)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250\text{ }\mu\text{A}$	1.0	2.0	3.0	V
$R_{DS(ON)}$	Drain-Source On-State Resistance	$V_{GS} = 10\text{ V}, I_D = 26\text{ A}$ $V_{GS} = 4.5\text{ V}, I_D = 20\text{ A}$	--	14.5 16.0	17.5 21.0	mR

**Off Characteristics**

$BV_{DSS}$	Drain-Source Breakdown Voltage	$V_{GS} = 0\text{ V}, I_D = 250\text{ }\mu\text{A}$	100	--	--	V
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS} = 80\text{ V}, V_{GS} = 0\text{ V}$	--	--	1	$\mu\text{A}$
$I_{GSSF}$	Gate-Body Leakage Current, Forward	$V_{GS} = 20\text{ V}, V_{DS} = 0\text{ V}$	--	--	100	nA
$I_{GSSR}$	Gate-Body Leakage Current, Reverse	$V_{GS} = -20\text{ V}, V_{DS} = 0\text{ V}$	--	--	-100	nA

**Dynamic Characteristics**

$R_G$	Gate Resistance	$V_{GS} = 0\text{ V}, V_{DS} = 0\text{ V}, f = 1\text{ MHz}$	--	1.0	--	R
$C_{ISS}$	Input Capacitance	$V_{DS} = 30\text{ V}, V_{GS} = 0\text{ V}, f = 1\text{ MHz}$	--	3045	3960	pF
$C_{OSS}$	Output Capacitance		--	265	--	
$C_{RSS}$	Reverse Transfer Capacitance		--	100	--	

**Switching Characteristics**

$t_{d(on)}$	Turn-On Delay Time	$V_{DD} = 30\text{ V}, V_{GS} = 10\text{ V}$ $R_G = 6.0\text{ }\Omega, R_L = 30\text{ }\Omega$ $I_D = 1.0\text{ A}$	--	21	38	ns
$T_r$	Turn-On Rise Time		--	8	15	
$t_{d(off)}$	Turn-Off Delay Time		--	70	126	
$t_f$	Turn-Off Fall Time		--	22	40	
$Q_g$	Total Gate Charge	$V_{DS} = 30\text{ V}, V_{GS} = 4.5\text{ V}, I_D = 26\text{ A}$	--	29	--	nC
$Q_g$	Total Gate Charge	$V_{DS} = 30\text{ V}, V_{GS} = 10\text{ V}, I_D = 26\text{ A}$	--	61	86	
$Q_{gs}$	Gate-Source Charge		--	10	--	
$Q_{gd}$	Gate-Drain Charge		--	11	--	

**Drain-Source Diode Characteristics**

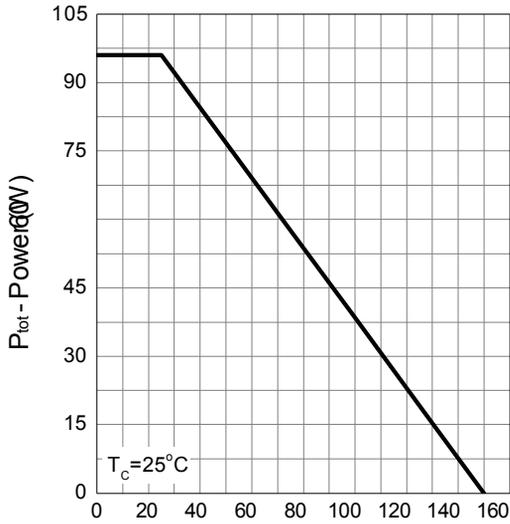
$V_{SD}$	Diode Forward Voltage	$V_{GS} = 0\text{ V}, I_S = 13\text{ A}$	--	0.8	1.3	V
$t_{rr}$	Reverse Recovery Time	$I_F = 26\text{ A}, di/dt = 100\text{ A}/\mu\text{s}$	--	54	--	ns
$Q_{rr}$	Reverse Recovery Charge		--	153	--	nC

**Notes ;**

1. Repetitive Rating : Pulse width limited by maximum junction temperature
2. Pulse Test : Pulse Width  $\leq 300\mu\text{s}$ , Duty Cycle  $\leq 2\%$
3. Guaranteed by design, not subject to production

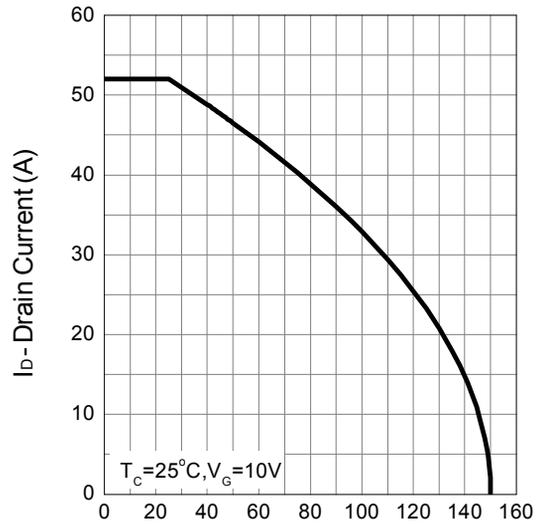
Typical Characteristics

Power Dissipation



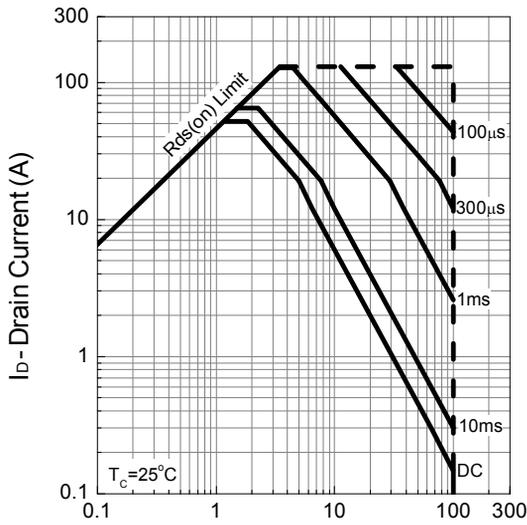
T<sub>j</sub> - Junction Temperature (°C)

Drain Current



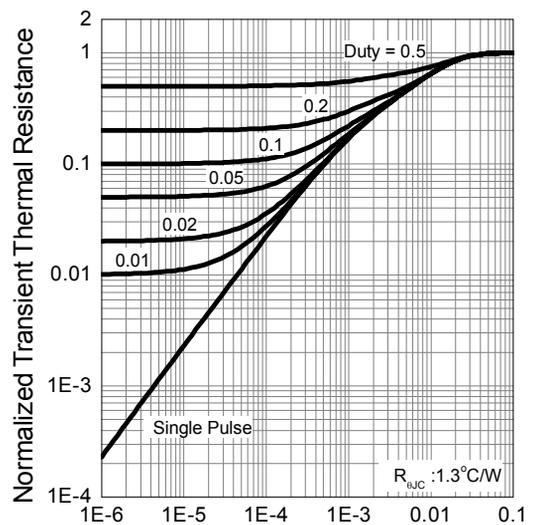
T<sub>j</sub> - Junction Temperature

Safe Operation Area



V<sub>DS</sub> - Drain - Source Voltage (V)

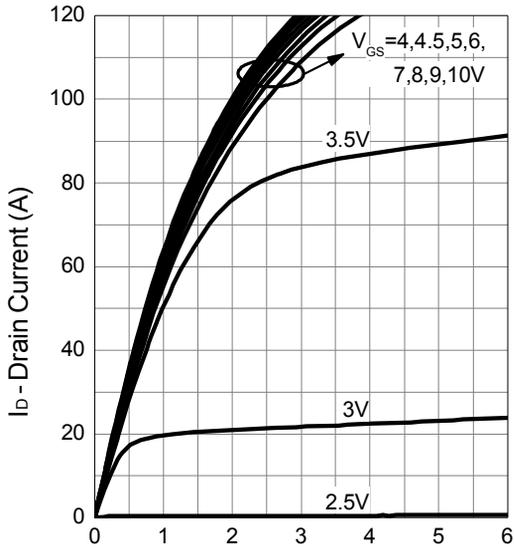
Thermal Transient Impedance



Square Wave Pulse Duration (sec)

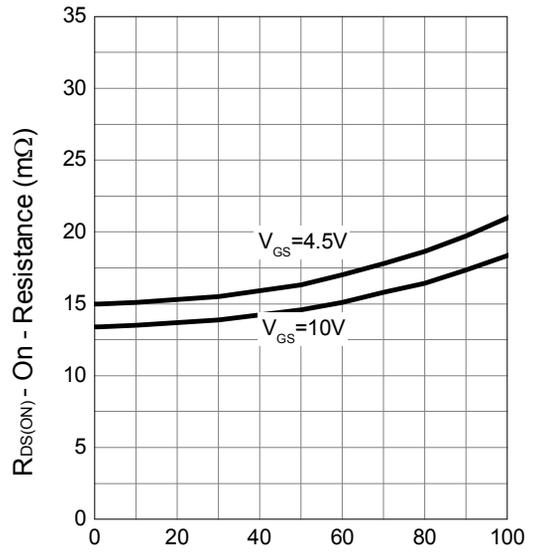
Typical Characteristics

Output Characteristics



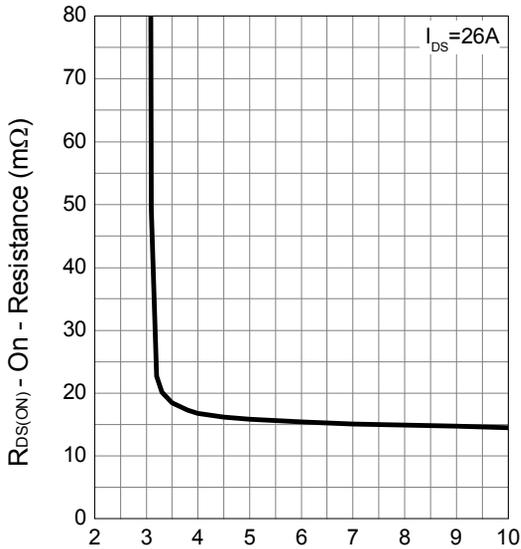
$V_{DS}$  - Drain - Source Voltage (V)

Drain-Source On Resistance



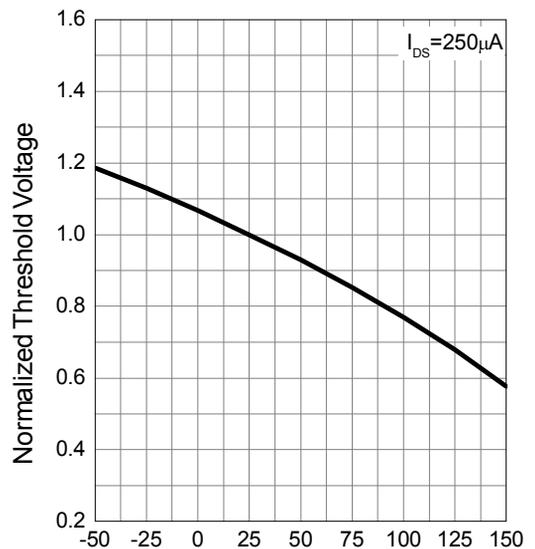
$I_D$  - Drain Current (A)

Gate-Source On Resistance



$V_{GS}$  - Gate - Source Voltage (V)

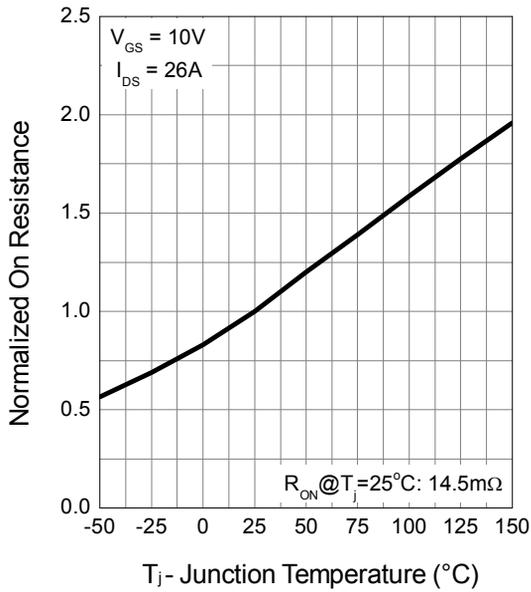
Gate Threshold Voltage



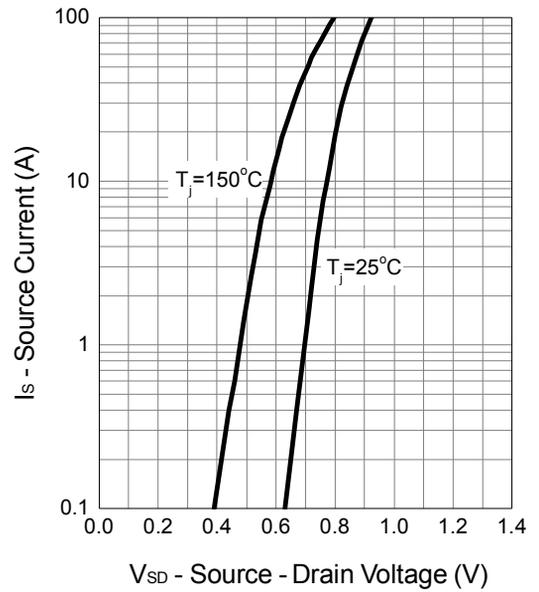
$T_J$  - Junction Temperature ( $^{\circ}C$ )

Typical Characteristics

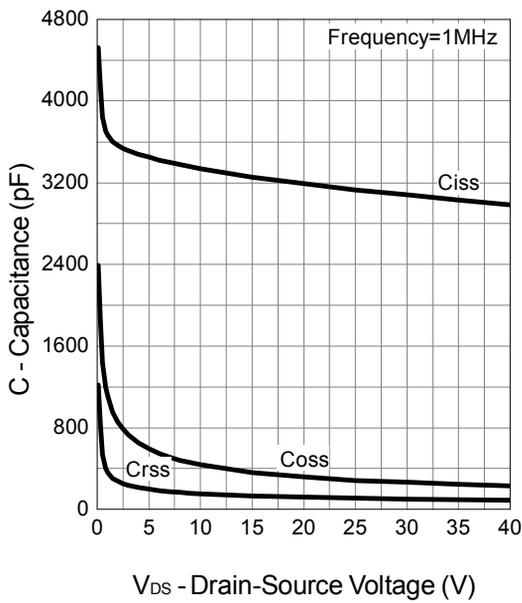
Drain-Source On Resistance



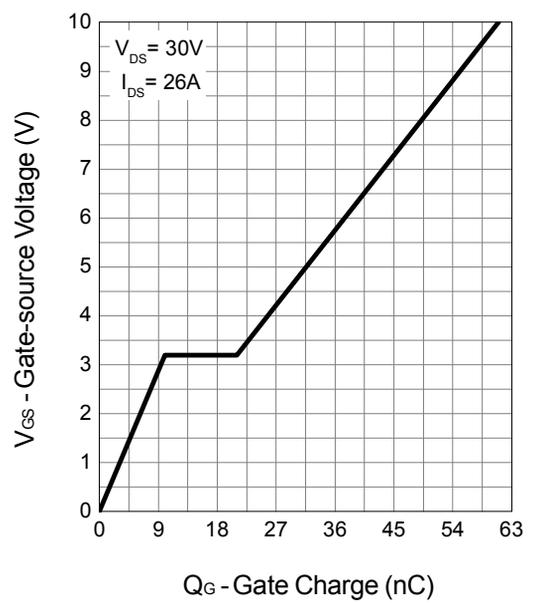
Source-Drain Diode Forward



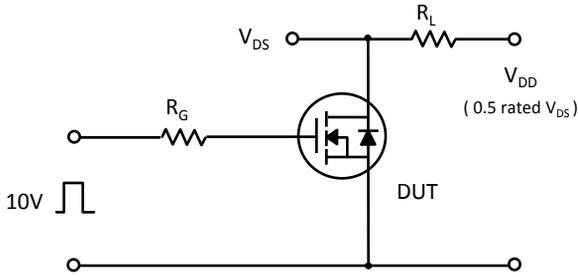
Capacitance



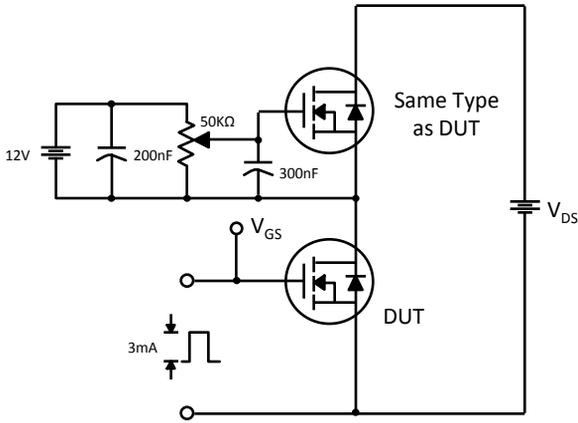
Gate Charge



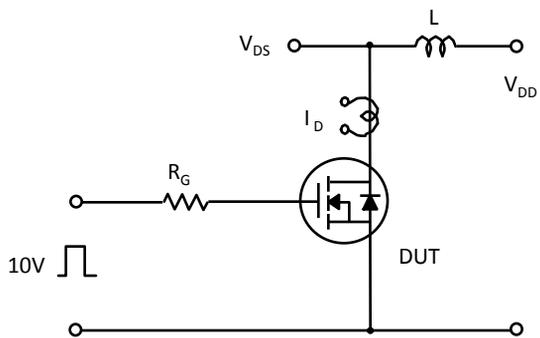
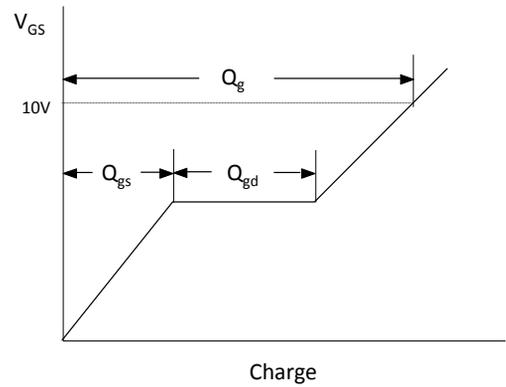
Characteristics Test Circuit & Waveform



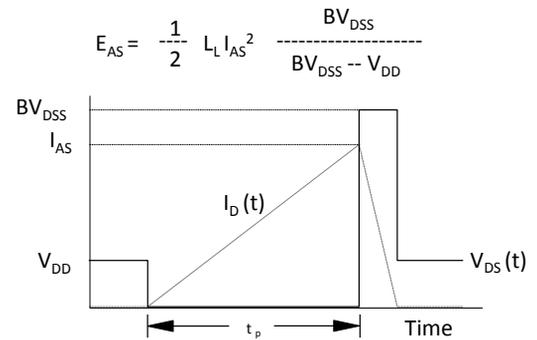
Resistive Switching Test Circuit & Waveforms



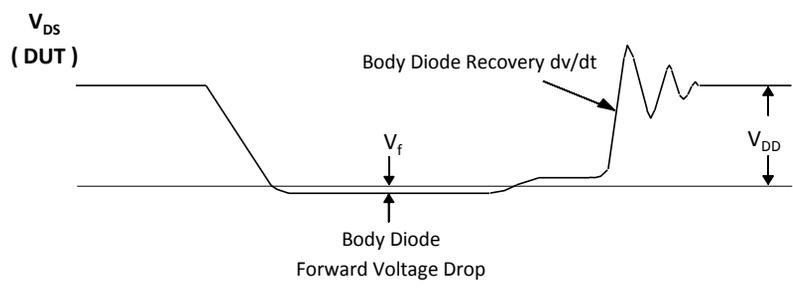
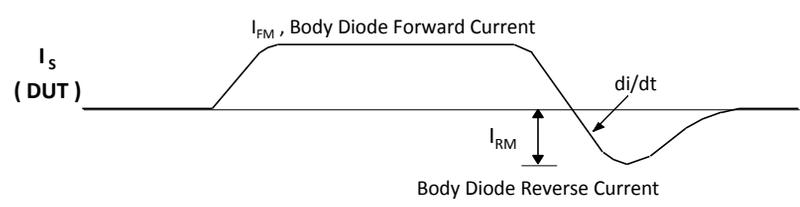
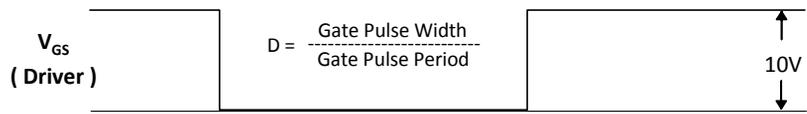
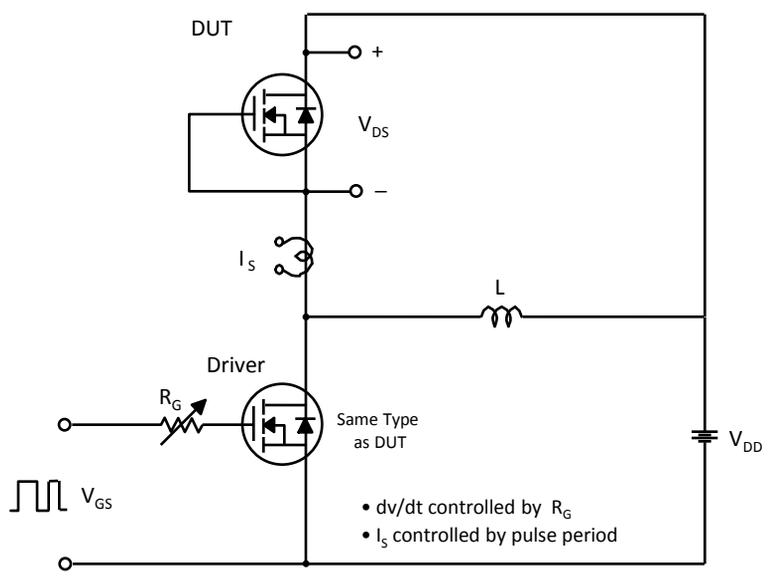
Gate Charge Test Circuit & Waveform



Unclamped Inductive Switching Test Circuit & Waveforms

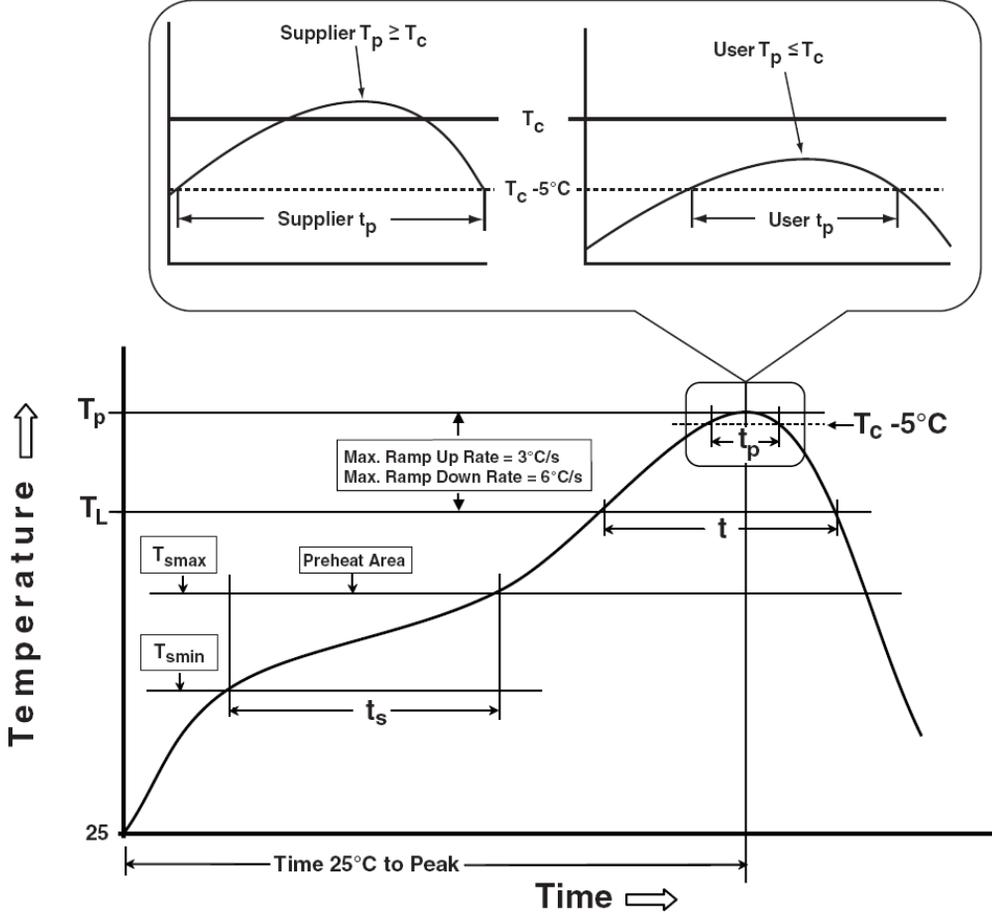


Characteristics Test Circuit & Waveform (continued)



Peak Diode Recovery dv/dt Test Circuit & Waveforms

Classification Profile



## Classification Reflow Profiles

Profile Feature	Sn-Pb Eutectic Assembly	Pb-Free Assembly
Preheat & Soak Temperature min ( $T_{smin}$ ) Temperature max ( $T_{smax}$ ) Time ( $T_{smin}$ to $T_{smax}$ ) ( $t_s$ )	100 °C 150 °C 60-120seconds	150 °C 200 °C 60-120seconds
Average ramp-up rate ( $T_{smax}$ to $T_p$ )	3 °C/second max.	3 °C/second max.
Liquidous temperature ( $T_L$ ) Time at liquidous ( $t_L$ )	183 °C 60-150seconds	217 °C 60-150seconds
Peak package body Temperature ( $T_p$ )*	See Classification Temp in table 1	See Classification Temp in table 2
Time ( $t_p$ )** within 5 °C of the specified classification temperature ( $T_c$ )	20** seconds	30**seconds
Average ramp-down rate ( $T_p$ to $T_{smax}$ )	6 °C/second max.	6 °C/second max.
Time 25 °C to peak temperature	6 minutes max.	8 minutes max.
* Tolerance for peak profile Temperature ( $T_p$ ) is defined as a supplier minimum and a user maximum. ** Tolerance for time at peak profile temperature ( $t_p$ ) is defined as a supplier minimum and a user maximum.		

Table 1. Sn Pb Eutectic Process – Classification Temperatures ( $T_c$ )

Package Thickness	Volume mm <sup>3</sup> < 350	Volume mm <sup>3</sup> ≥ 350
< 2.5 mm	235 °C	220 °C
≥ 2.5 mm	220 °C	220 °C

Table 2. Pb-free Process – Classification Temperatures ( $T_c$ )

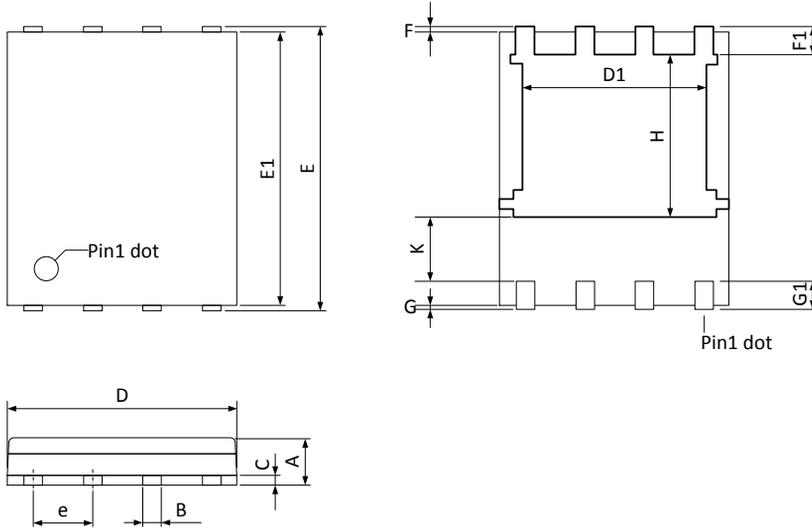
Package Thickness	Volume mm <sup>3</sup> < 350	Volume mm <sup>3</sup> : 350-2000	Volume mm <sup>3</sup> ≥ 2000
< 1.6 mm	260 °C	260 °C	260 °C
1.6 - 2.5 mm	260 °C	250 °C	245 °C
≥ 2.5 mm	250 °C	245 °C	245 °C

## Reliability Test Program

Test Item	Method	Description
Solder ability	JESD-22, B102	5 Sec , 245 °C
HTRB	JESD-22, A108	1000 Hrs, 80% of VDS max @ $T_{jmax}$
HTGB	JESD-22, A108	1000 Hrs, 100% of VGS max @ $T_{jmax}$
PCT	JESD-22, A102	168 Hrs, 100%RH, 2atm, 121 °C
TCT	JESD-22, A104	500 Cycl es, -65 °C~150 °C

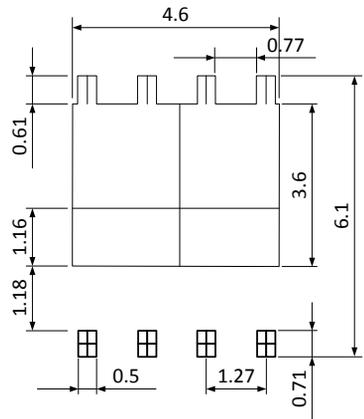
Package Dimension

DFN 5x6 Package Outline



	DFN 5x6			
	Millimeter		Inches	
	Min.	Max.	Min.	Max.
A	0.90	1.20	0.035	0.047
B	0.30	0.51	0.012	0.020
C	0.19	0.25	0.007	0.010
D	4.80	5.30	0.189	0.209
D1	3.60	4.40	0.141	0.173
E	5.90	6.20	0.232	0.244
E1	5.50	5.80	0.217	0.228
e	1.27 BSC		0.050 BSC	
F	0.05	0.30	0.002	0.012
F1	0.35	0.75	0.014	0.030
G	0.05	0.30	0.002	0.012
G1	0.35	0.75	0.014	0.030
H	3.34	3.90	0.131	0.154
K	0.762	-	0.030	-

Recommended Land Pattern



Note : Dimension D, D1 and E1 do not include mold flash or protrusions.  
Mold flash or protrusions shall not exceed 10 mil.